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Michael Hausner was born in 1949 in Ukraine (former USSR republic) and immigrated to Israel with his parents and sister in 1959. In 1968, he graduated from technical school as a technician/tool operator, and in 1977 he graduated from the Technion (Israel Institute of Technology), External Studies Section, as a Certified Senior Electrician. In 1990, Hausner became a Certified Practical Electronics Engineer after studying at ORT Bialik College, and in 1996 he graduated from the Standards Institution of Israel (SII) as a Certified Quality Auditor. In 2001, he became a Senior Certified Teacher at the Practical Engineering School in the Technion. His quality management system has been certified for ISO 9001:2008 by the SII since 2013.

Since 1984, Hausner has spent his time in two fields:

- Optics, including the inspection and testing of optical elements (incoming and at the source of production), audits of optical element suppliers, writing procedures for optics inspections, handling nonconforming optical elements and corrective actions, consulting, and training inspectors.
- Quality assurance, including the oversight of QA training courses at several colleges (over 1500 hours of instruction).

He currently works as an independent optics inspector who assists various companies in Israel.